

Resource Summary Report

Generated by [RRID](#) on Aug 4, 2026

JEOL: JXA-iSP100 Electron Probe Microanalyzer (EPMA)

RRID:SCR_020198

Type: Tool

Proper Citation

JEOL: JXA-iSP100 Electron Probe Microanalyzer (EPMA) (RRID:SCR_020198)

Resource Information

URL: <https://www.jeolusa.com/PRODUCTS/Microprobe-EPMA-and-Auger/JXA-iSP100>

Proper Citation: JEOL: JXA-iSP100 Electron Probe Microanalyzer (EPMA) (RRID:SCR_020198)

Description: Electron probe microanalyzer that provides both high imaging resolution and analytical resolution with very high and stable probe current for analytical performance with new algorithms for auto functions of both SEM column and optical microscope.

Resource Type: instrument resource

Keywords: Jeol, JEOL, Electron Probe Microanalyzer, Instrument Equipment, USEdit,

Availability: Commercially available

Resource Name: JEOL: JXA-iSP100 Electron Probe Microanalyzer (EPMA)

Resource ID: SCR_020198

Alternate IDs: Model_Number_JXA_iSP100

Record Creation Time: 20220129T080349+0000

Record Last Update: 20260801T190645+0000

Ratings and Alerts

No rating or validation information has been found for JEOL: JXA-iSP100 Electron Probe Microanalyzer (EPMA).

No alerts have been found for JEOL: JXA-iSP100 Electron Probe Microanalyzer (EPMA).

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.